

Form PTO 1449  
(Modified)U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.  
237565US0SERIAL NO.  
10/812,956

## LIST OF REFERENCES CITED BY APPLICANT

APPLICANT

Christine MEUNIER

FILING DATE

March 31, 2004

GROUP

1615

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/B.S.F./	AA	2004/0219123	11/4/04	Astruc, et al.			
	AB	2002/0064540	5/30/02	Allec, et al.			
	AC	2002/0054928	5/9/02	Picard-Lesboueyries			
	AD	5,552,446	9/3/96	Candau, et al.			
	AE	6,007,799	12/28/99	Lee, et al.			
/B.S.F./	AF	6,294,157	9/25/01	Rubinstenn, et al.			
	AG						
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## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
/B.S.F./	AO	JP2003-81757	3/19/03	Japan (English Abstract Provided)		X
	AP	JP2003-81758	3/19/03	Japan (English Abstract Provided)		X
	AQ	JP2000-53555	2/22/00	Japan (English Abstract Provided)		X
	AR	JP7-256086	10/9/95	Japan (Equivalent to US 5,552,446)		X
	AS	JP10-324616	12/8/98	Japan (Equivalent to EP0875235)		X
	AT	EP 0 875 235	11/4/98	EPO (Equivalent to JP10-324616)	X	
	AU	EP 1 216 685	6/26/02	EPO (Equivalent to JP2002-322045)	X	
/B.S.F./	AV	JP2002-518421	6/25/02	Japan (English Abstract Provided)		X

## OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	<del>English Translation of Japanese Office Action dated August 9, 2005 for Application No. 2004 114610, 6 pp.</del> not a published document	
	AX		
	AY		
	AZ		

☐ Additional References sheet(s) attached

Examiner /Barbara S. Frazier/

Date Considered 09/17/2007

\*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 237565US0		SERIAL NO. 10/812,956	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Christine MEUNIER			
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<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES                  NO		
/B.S.F./	AO	JP2002-138032	5/14/02	Japan (English Translation Attached) (Equivalent to CA2351925)	X		
	AP	CA 2 351 925	12/27/01	Canada	X		
	AQ	WO 03/011243	2/13/03	WIPO (Equivalent to US 2004/0219123)		X	
	AR	JP2002-80341	3/19/02	Japan (Equivalent to US 2002/0064540) (English Abstract Provided)		X	
	AS	JP2001-114632	4/24/01	Japan (Equivalent to US 6,294,157) (English Abstract Provided)		X	
	AT	JP2002-80323	3/19/02	Japan (Equivalent to US 2002/0054928) (English Abstract Provided)		X	
	AU	JP2004-10518	2/15/04	Japan (English Abstract Provided)		X	
/B.S.F./	AV	JP2002-322045	11/8/02	Japan (English Translation Attached) (Equivalent to EP1216685)	X		
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
	AW						
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner /Barbara S. Frazier/					Date Considered 09/17/2007		
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				FILING DATE Herewith		GROUP	
<b>U.S. PATENT DOCUMENTS</b>							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
/B.S.F./	AA	5,362,482	11/08/94	Yoneyama et al.			
/B.S.F./	AB	6,007,799	12/28/99	Lee et al.			
/B.S.F./	AC	6,383,503 B1	05/07/02	Bleckmann et al.			
	AD						
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<b>FOREIGN PATENT DOCUMENTS</b>							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES      NO		
	<del>AO</del>	<del>EP 0 304 775</del>	<del>00/01/00</del>	<del>Europe</del>	<del>no translation</del>		
	AP						
	AQ						
	AR						
	AS						
	AT						
	AU						
	AV						
<b>OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)</b>							
/B.S.F./	AW	DATABASE WPI Section Ch, Week 199912; Derwent Publications Ltd., London, G; Class A26, AN 1999-136679 XP002265284 & JP 11 005712 A; January 12, 1999					
	AX						
	AY						
	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
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